# MSKSEMI 美森科













**ESD** 

TVS

TSS

MOV

GDI

PLED

# MS35N06

**Product specification** 





#### **General Description**

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

#### **General Features**

- 60V,35A, RDS(ON)=23mΩ@VGS=10V
- Improved dv/dt capability
- Fast switching
- Green Device Available

## **Application**

- Motor Drive
- Power Tools
- LED Lighting

### **Reference News**

PACKAGE OUTLINE	Pin Configuration	Marking
	G	MSKSEMI 35N06 MS06N
TO-252	s	



# **Absolute Maximum Ratings** Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	60	V
Vgs	Gate-Source Voltage	±20	V
l <sub>D</sub>	Drain Current – Continuous (Tc=25°C)	35	А
ID	Drain Current – Continuous (Tc=100°C)	18	А
Ірм	Drain Current – Pulsed <sup>1</sup>	140	А
Pp	Power Dissipation (Tc=25°C)	40	W
FU	Power Dissipation – Derate above 25°C	0.32	W/°C
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	℃

## **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		62	°C/W
Reuc	Thermal Resistance Junction to Case		3.1	°C/W

# Electrical Characteristics (TJ=25 $^{\circ}$ C , unless otherwise noted)

#### Off Characteristics

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	60			V
△BV <sub>DSS</sub> /△T <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient Reference to 25°C , I <sub>D</sub> =1mA			0.06		V/°C
lpss	Drain Source Leakage Current	V <sub>DS</sub> =60V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	uA
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =48V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			10	uA
lgss	Gate-Source Leakage Current	V <sub>GS=</sub> ±20V , V <sub>DS</sub> =0V			±100	nA



#### On Characteristics

Rds(on)	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V , I <sub>D</sub> =10A		23	31	mΩ
Otatic Drain-Source Off-Resistance		V <sub>GS</sub> =4.5V , I <sub>D</sub> =5A		30	38	mΩ
VGS(th)	Gate Threshold Voltage	-Vgs=Vps , Ip =250uA	1.0	1.6	2.5	V
△VGS(th)	V <sub>GS(th)</sub> Temperature Coefficient			-4.6		mV/°C
gfs	Forward Transconductance	VDS=10V , ID=8A		11		S

#### Dynamic and switching Characteristics

Dynamic	and Switching	Onaracteristics			
Qg	Total Gate Charge <sup>3, 4</sup>			16.4	
Qgs	Gate-Source Charge <sup>3, 4</sup>	ge <sup>3</sup> · <sup>4</sup> V <sub>DS</sub> =30V , V <sub>GS</sub> =10V , I <sub>D</sub> =10A		3.1	 nC
Qgd	Gate-Drain Charge <sup>3, 4</sup>			3.7	
Td(on)	Turn-On Delay Time <sup>3,4</sup>			4.6	
Tr	Rise Time <sup>3, 4</sup>	$V_{DD}$ =30V , $V_{GS}$ =10V , $R_{G}$ =6 $\Omega$		14.8	 
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>3, 4</sup>	ID=1A		27.2	 ns
Tf	Fall Time <sup>3, 4</sup>	ID- IA		7.8	
Ciss	Input Capacitance			1180	
Coss	Output Capacitance	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , F=1MHz		80	 pF
Crss	Reverse Transfer Capacitance	е		52	
Rg	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, F=1MHz		1.3	 Ω

# Drain- Source Diode Characteristics and Maximum Ratings

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			35	Α
Ism	Pulsed Source Current	vg-vb-ov , r orce ourient			70	Α
VsD	Diode Forward Voltage	V <sub>G</sub> s=0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1.2	V

#### Note:

- 1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
- 2.  $V_{DD}$ =50V, $V_{GS}$ =10V,L=0. 1mH, $I_{AS}$ =23A., $R_{G}$ =25 $\Omega$ , Starting  $T_{J}$ =25 $^{\circ}$ C
- 3. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%.
- 4. Essentially independent of operating temperature.



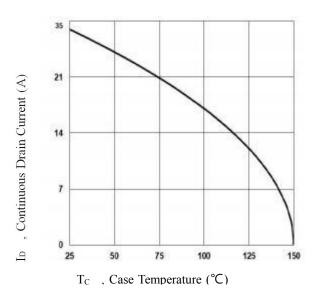


Fig.1 Typical Output Characteristics

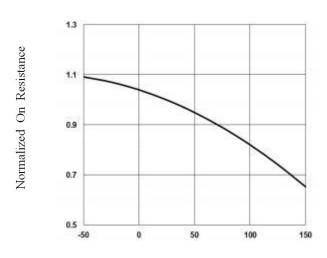


Fig. 3 Normalized RDSON vs. T<sub>J</sub>

TJ,Junction Temperature (°C)

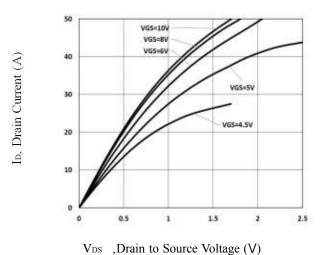


Fig. 5 Typical Output Characteristics

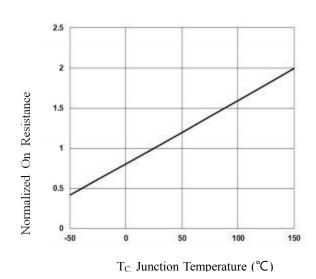


Fig.2 Continuous Drain Current vs. Tc

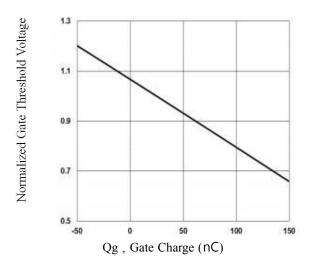


Fig.4 Gate Charge Waveform

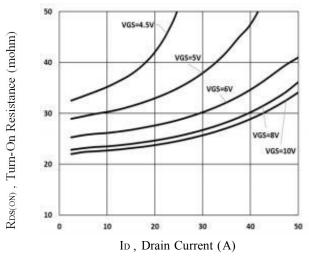
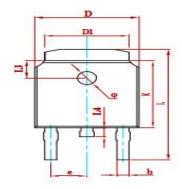


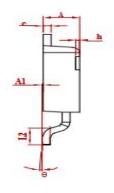
Fig.6 Turn-On Resistance vs. ID

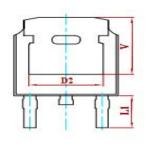




# PACKAGE MECHANICAL DATA

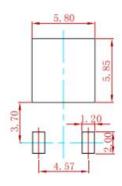






Symbol	Dimensions In Millimeters		Dimensions	In Inches
Symbol	Min.	Max.	Min.	Max.
Α	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.635	0.770	0.025	0.030
С	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830	REF.	0.190	REF.
E	6.000	6.200	0.236	0.244
е	2.186	2.386	0.086	0.094
L	9.712	10.312	0.382	0.406
L1	2.900 REF.		0.114	REF.
L2	1.400	1.700	0.055	0.067
L3	1.600	REF.	0.063	REF.
L4	0.600	1.000	0.024	0.039
Ф	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.250	REF.	0.207	REF.

# **Suggested Pad Layout**



#### Note:

- 1 Controlling dimension in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only,

#### **REEL SPECIFICATION**

P/N	PKG	QTY
MS35N06	TO-252	2500



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